

Notice of References Cited

Application/Control No.

09/683,546

Applicant(s)/Patent Under
Reexamination
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Examiner

A. M. Thompson

Art Unit

2825

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,028,995	02-2000	Jetton et al.	716/3
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NON-PATENT DOCUMENTS

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	U	Stievano et al., Parametric Macromodels of Digital I/O Ports, IEEE Transactions on Advanced Packaging, pages 255-264, May 2002.
	V	Stievano et al., Behavioral Modeling of Digital IC Input and Output Ports, Electrical Performance of Electronic Packaging, pages 331-334, October 2001.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.